Seminar Series

Degradation Modeling and Reliability Testing: Research Developments & Trends

Professor TANG Loon Ching,
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Date: 11 December 2019 (Wednesday)
Time: 10:30 am - 11:30 am
Venue: P7510, Yeung Kin Man Academic Building (YEUNG), City University of Hong Kong

Abstract

In this talk we shall give some of the historical accounts on degradation modelling and reliability testing. This is followed by some developments on accelerated reliability testing motivated by real world applications. In particular, a Bayesian approach will be discussed and its solution is compared with that of conventional approach. We then discuss a range of related problems for future research and development.

About the Speaker

Professor TANG Loon Ching is a Professor at the Dept of Industrial & Systems Engineering (ISE) and the Director of Temasek Defence Systems Institute in National Univ of Singapore. LC Tang obtained his PhD in the field of operations research from Cornell Univ in 1992. He has published widely in many leading international journals. He was presented the IIE Transactions 2010 Best Application Paper Award and the prestigious Ralph A. Evans/P.K. McElroy Awards for the best paper presented at 2011 RAMS. LC Tang is the editor of Quality and Reliability Engineering International and has been on the editorial review board of the Journal of Quality Technology.